Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the Executive Secretary of the International Union of Crystallography (J. K. King, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England).


J. D. Hanawalt Powder Diffraction Award

The JCPDS—International Centre for Diffraction Data is seeking candidates for the J. D. Hanawalt Powder Diffraction Award. The award is presented every three years for an important recent contribution to the field of powder diffraction. The award consists of a certificate and $1000. The awardee is expected to submit an abstract and present a paper on the work being recognized at a forthcoming Powder Diffraction/Crystallographic Meeting. The recipient’s travel expenses to the meeting will be provided. Work eligible for consideration must have been published between August 1984 and August 1989. The selection committee welcomes suggestions, nominations, and documentation of accomplishments for possible recipients through 10 January 1990. Contact: Benjamin Post, 108 Church Street, W. Roxbury, MA 02132, USA.

New Commercial Products

Announcements of new commercial products are published by the Journal of Applied Crystallography free of charge. The descriptions, up to 300 words or the equivalent if a figure is included, should give the price and the manufacturer’s full address. Full or partial inclusion is subject to the Editor’s approval and to the space available. All correspondence should be sent to the Editor, Professor M. Schlenker, Editor Journal of Applied Crystallography, Laboratoire Louis Neel du CNRS, BP1968, F 38042 Grenoble CEDEX, France.

The International Union of Crystallography can assume no responsibility for the accuracy of the claims made. A copy of the version sent to the printer is sent to the company concerned.


More Power for Philips XRD Software

The latest version of Philips APD1700 X-ray diffraction software features an increased range of analytical modules and facilities to improve the measurement performance and data interpretation. Designed for VAX and PDP computers, it is the first XRD package to offer the advantage of a windows-based user interface for the DEC VMS and VAX operating systems. APD1700 now includes enhanced facilities for residual-stress, texture, line-profile and crystallographic analysis as well as for automatic phase identification and quantitative determination. It has also been designed to allow the introduction of users’ own programs and special routines.

Pattern treatment is based on a special multi-pass search procedure which ensures rapid reliable detection of sharp and broad peaks. A new profile-fitting module for detecting hidden peaks and resolving overlapping lines further increases the powerful qualitative analysis capability.

Also new is an extended graphics display module, with a flexible and visually attractive three-dimensional display package for easy comparison of multiple scans.

The JCPDS Powder Diffraction File can be supplied on magnetic disk in a packed format (Level 1) or as the Philips total access diffraction database on CD-ROM, which contains the complete card image (for VAX only). Pattern matching is speeded by the ability to create user-specific sub-files from either database source or in fact a combination.

Running under the multi-user, multi-tasking VMS and RSX operating systems, APD1700 offers economical centralized control of multiple diffractometers – while operators work simultaneously on program set-up, measurement and examination of results. Thus making optimum cost effective use of investment.

Philips Scientific, York Street, Cambridge CB1 2PX, England.

Books Received

The following books have been received by the Editor: Brief and generally uncritical notices are given of works of marginal crystallographic interest; occasionally a book of fundamental interest is included under this heading because of difficulty in finding a suitable reviewer without great delay.

